AMD Xilinx - XCS05-4VQ100C Datasheet

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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	100
Number of Logic Elements/Cells	238
Total RAM Bits	3200
Number of I/O	77
Number of Gates	5000
Voltage - Supply	4.75V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	100-TQFP
Supplier Device Package	100-VQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xcs05-4vq100c

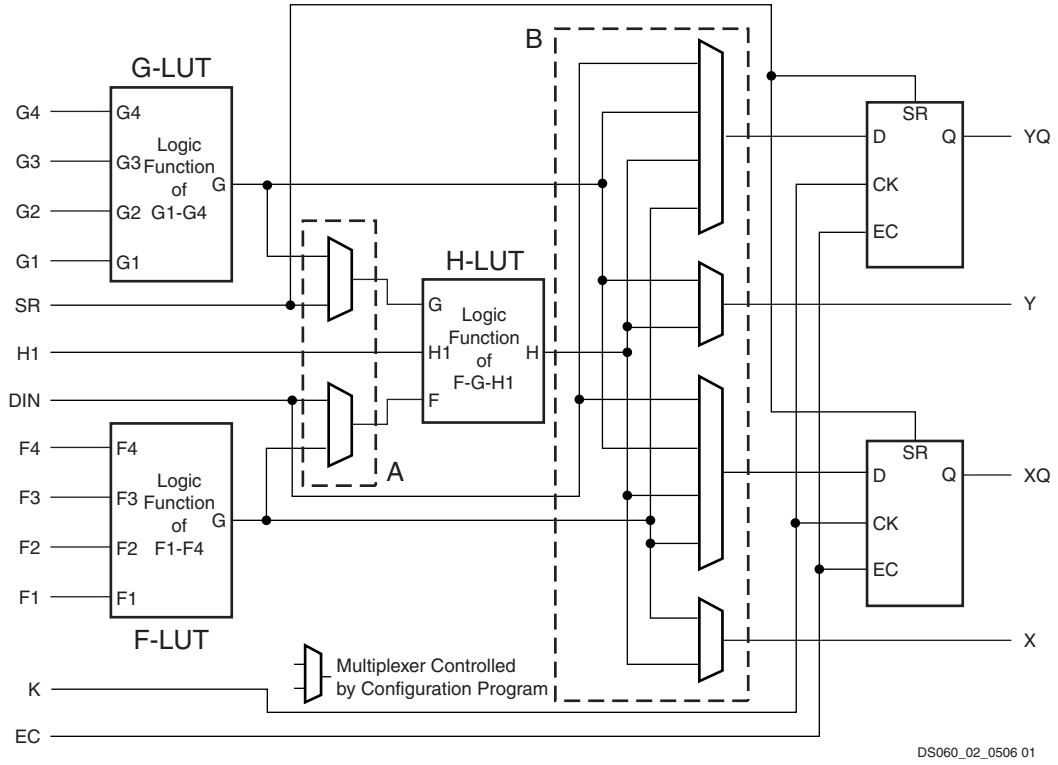


Figure 2: **Spartan/XL Simplified CLB Logic Diagram (some features not shown)**

A CLB can implement any of the following functions:

- Any function of up to four variables, plus any second function of up to four unrelated variables, plus any third function of up to three unrelated variables

  Note: When three separate functions are generated, one of the function outputs must be captured in a flip-flop internal to the CLB. Only two unregistered function generator outputs are available from the CLB.
- Any single function of five variables
- Any function of four variables together with some functions of six variables
- Some functions of up to nine variables.

Implementing wide functions in a single block reduces both the number of blocks required and the delay in the signal path, achieving both increased capacity and speed.

The versatility of the CLB function generators significantly improves system speed. In addition, the design-software tools can deal with each function generator independently. This flexibility improves cell usage.

Flip-Flops

Each CLB contains two flip-flops that can be used to register (store) the function generator outputs. The flip-flops and function generators can also be used independently (see Figure 2). The CLB input DIN can be used as a direct input to either of the two flip-flops. H1 can also drive either flip-flop via the H-LUT with a slight additional delay.

The two flip-flops have common clock (CK), clock enable (EC) and set/reset (SR) inputs. Internally both flip-flops are also controlled by a global initialization signal (GSR) which is described in detail in **Global Signals: GSR and GTS**, page 20.

Latches (Spartan-XL Family Only)

The Spartan-XL family CLB storage elements can also be configured as latches. The two latches have common clock (K) and clock enable (EC) inputs. Functionality of the storage element is described in Table 2.

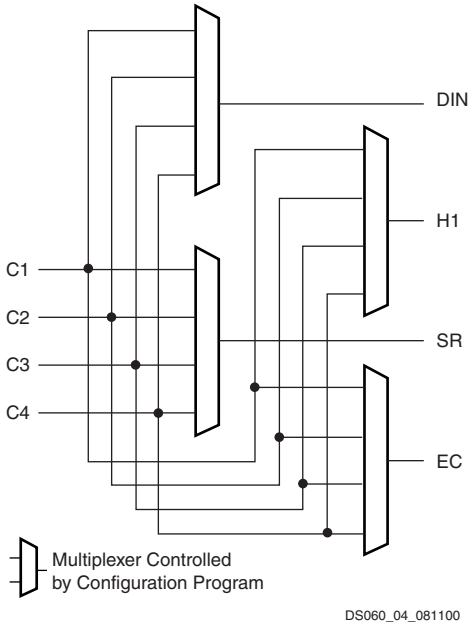


Figure 4: **CLB Control Signal Interface**

The four internal control signals are:

- EC: Enable Clock
- SR: Asynchronous Set/Reset or H function generator Input 0
- DIN: Direct In or H function generator Input 2
- H1: H function generator Input 1.

Input/Output Blocks (IOBs)

User-configurable input/output blocks (IOBs) provide the interface between external package pins and the internal logic. Each IOB controls one package pin and can be configured for input, output, or bidirectional signals. Figure 6 shows a simplified functional block diagram of the Spartan/XL FPGA IOB.

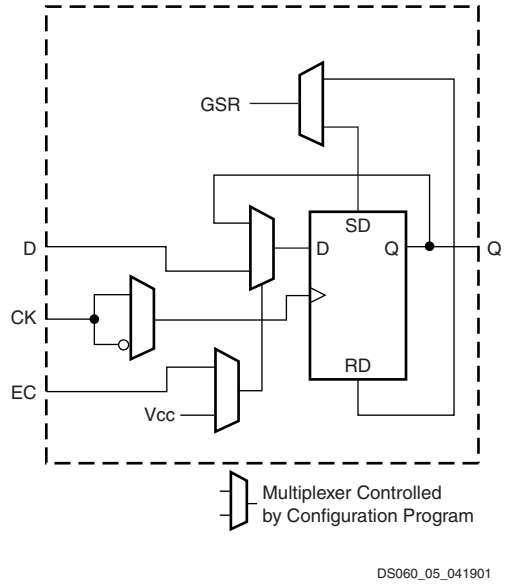


Figure 5: **IOB Flip-Flop/Latch Functional Block Diagram**

IOB Input Signal Path

The input signal to the IOB can be configured to either go directly to the routing channels (via I1 and I2 in Figure 6) or to the input register. The input register can be programmed as either an edge-triggered flip-flop or a level-sensitive latch. The functionality of this register is shown in Table 3, and a simplified block diagram of the register can be seen in Figure 5.

Table 3: **Input Register Functionality**

Mode	CK	EC	D	Q
Power-Up or GSR	X	X	X	SR
Flip-Flop	⌐	1*	D	D
	0	X	X	Q
Latch	1	1*	X	Q
	0	1*	D	D
Both	X	0	X	Q

Legend:

X	Don't care.
⌐	Rising edge (clock not inverted).
SR	Set or Reset value. Reset is default.
0*	Input is Low or unconnected (default value)
1*	Input is High or unconnected (default value)

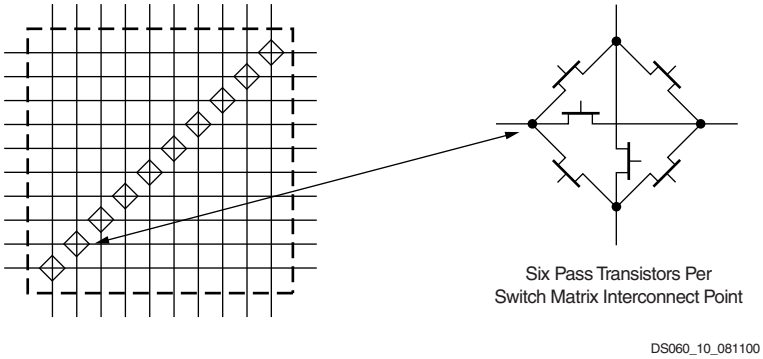


Figure 10: **Programmable Switch Matrix**

Double-Length Lines

The double-length lines consist of a grid of metal segments, each twice as long as the single-length lines: they run past two CLBs before entering a PSM. Double-length lines are grouped in pairs with the PSMs staggered, so that each line goes through a PSM at every other row or column of CLBs (see Figure 8).

There are four vertical and four horizontal double-length lines associated with each CLB. These lines provide faster signal routing over intermediate distances, while retaining routing flexibility.

Longlines

Longlines form a grid of metal interconnect segments that run the entire length or width of the array. Longlines are intended for high fan-out, time-critical signal nets, or nets that are distributed over long distances.

Each Spartan/XL device longline has a programmable splitter switch at its center. This switch can separate the line into two independent routing channels, each running half the width or height of the array.

Routing connectivity of the longlines is shown in Figure 8. The longlines also interface to some 3-state buffers which is described later in **3-State Long Line Drivers**, page 19.

I/O Routing

Spartan/XL devices have additional routing around the IOB ring. This routing is called a VersaRing. The VersaRing facilitates pin-swapping and redesign without affecting board layout. Included are eight double-length lines, and four longlines.

Global Nets and Buffers

The Spartan/XL devices have dedicated global networks. These networks are designed to distribute clocks and other high fanout control signals throughout the devices with minimal skew.

Four vertical longlines in each CLB column are driven exclusively by special global buffers. These longlines are in addition to the vertical longlines used for standard interconnect. In the 5V Spartan devices, the four global lines can be driven by either of two types of global buffers; Primary Global buffers (BUFGP) or Secondary Global buffers (BUFGS). Each of these lines can be accessed by one particular Primary Global buffer, or by any of the Secondary Global buffers, as shown in Figure 11. In the 3V Spartan-XL devices, the four global lines can be driven by any of the eight Global Low-Skew Buffers (BUFGLS). The clock pins of every CLB and IOB can also be sourced from local interconnect.

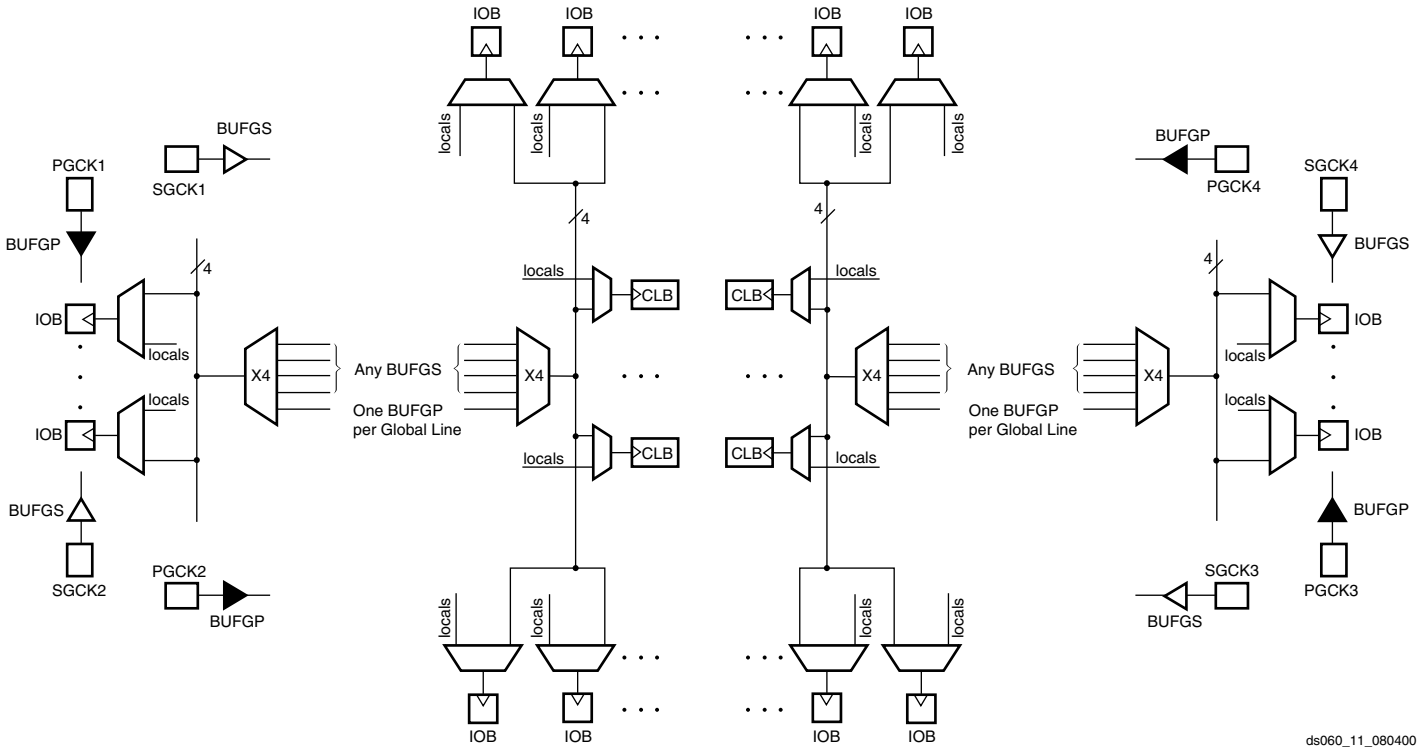


Figure 11: **5V Spartan Family Global Net Distribution**

The four Primary Global buffers offer the shortest delay and negligible skew. Four Secondary Global buffers have slightly longer delay and slightly more skew due to potentially heavier loading, but offer greater flexibility when used to drive non-clock CLB inputs. The eight Global Low-Skew buffers in the Spartan-XL devices combine short delay, negligible skew, and flexibility.

The Primary Global buffers must be driven by the semi-dedicated pads (PGCK1-4). The Secondary Global buffers can be sourced by either semi-dedicated pads (SGCK1-4) or internal nets. Each corner of the device has one Primary buffer and one Secondary buffer. The Spartan-XL family has eight global low-skew buffers, two in each corner. All can be sourced by either semi-dedicated pads (GCK1-8) or internal nets.

Using the library symbol called BUFG results in the software choosing the appropriate clock buffer, based on the timing requirements of the design. A global buffer should be specified for all timing-sensitive global signal distribution. To use a global buffer, place a BUFGP (primary buffer), BUFGS (secondary buffer), BUFGLS (Spartan-XL family global low-skew buffer), or BUFG (any buffer type) element in a schematic or in HDL code.

Advanced Features Description

Distributed RAM

Optional modes for each CLB allow the function generators (F-LUT and G-LUT) to be used as Random Access Memory (RAM).

Read and write operations are significantly faster for this on-chip RAM than for off-chip implementations. This speed advantage is due to the relatively short signal propagation delays within the FPGA.

Memory Configuration Overview

There are two available memory configuration modes: single-port RAM and dual-port RAM. For both these modes, write operations are synchronous (edge-triggered), while read operations are asynchronous. In the single-port mode, a single CLB can be configured as either a 16 x 1, (16 x 1) x 2, or 32 x 1 RAM array. In the dual-port mode, a single CLB can be configured only as one 16 x 1 RAM array. The different CLB memory configurations are summarized in Table 8. Any of these possibilities can be individually programmed into a Spartan/XL FPGA CLB.

Table 8: **CLB Memory Configurations**

Mode	16 x 1	(16 x 1) x 2	32 x 1
Single-Port	√	√	√
Dual-Port	√	–	–

- The 16 x 1 single-port configuration contains a RAM array with 16 locations, each one-bit wide. One 4-bit address decoder determines the RAM location for write and read operations. There is one input for writing data and one output for reading data, all at the selected address.
- The (16 x 1) x 2 single-port configuration combines two 16 x 1 single-port configurations (each according to the preceding description). There is one data input, one data output and one address decoder for each array. These arrays can be addressed independently.
- The 32 x 1 single-port configuration contains a RAM array with 32 locations, each one-bit wide. There is one data input, one data output, and one 5-bit address decoder.
- The dual-port mode 16 x 1 configuration contains a RAM array with 16 locations, each one-bit wide. There are two 4-bit address decoders, one for each port. One port consists of an input for writing and an output for reading, all at a selected address. The other port consists of one output for reading from an independently selected address.

The appropriate choice of RAM configuration mode for a given design should be based on timing and resource requirements, desired functionality, and the simplicity of the design process. Selection criteria include the following: Whereas the 32 x 1 single-port, the (16 x 1) x 2 single-port, and the 16 x 1 dual-port configurations each use one entire CLB, the 16 x 1 single-port configuration uses only one half of a CLB. Due to its simultaneous read/write capability, the dual-port RAM can transfer twice as much data as the single-port RAM, which permits only one data operation at any given time.

CLB memory configuration options are selected by using the appropriate library symbol in the design entry.

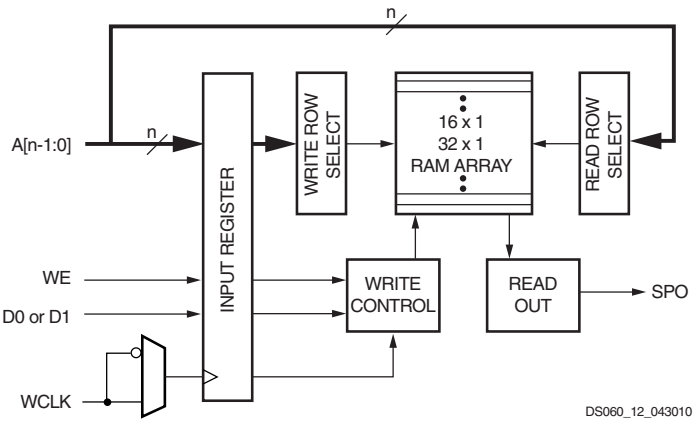
Single-Port Mode

There are three CLB memory configurations for the single-port RAM: 16 x 1, (16 x 1) x 2, and 32 x 1, the functional organization of which is shown in Figure 12.

The single-port RAM signals and the CLB signals (Figure 2, page 4) from which they are originally derived are shown in Table 9.

Table 9: **Single-Port RAM Signals**

RAM Signal	Function	CLB Signal
D0 or D1	Data In	DIN or H1
A[3:0]	Address	F[4:1] or G[4:1]
A4 (32 x 1 only)	Address	H1
WE	Write Enable	SR
WCLK	Clock	K
SPO	Single Port Out (Data Out)	F_{OUT} or G_{OUT}



Notes:
1. The (16 x 1) x 2 configuration combines two 16 x 1 single-port RAMs, each with its own independent address bus and data input. The same WE and WCLK signals are connected to both RAMs.
2. n = 4 for the 16 x 1 and (16 x 1) x 2 configurations. n = 5 for the 32 x 1 configuration.

Figure 12: **Logic Diagram for the Single-Port RAM**

Writing data to the single-port RAM is essentially the same as writing to a data register. It is an edge-triggered (synchronous) operation performed by applying an address to the A inputs and data to the D input during the active edge of WCLK while WE is High.

The timing relationships are shown in Figure 13. The High logic level on WE enables the input data register for writing. The active edge of WCLK latches the address, input data, and WE signals. Then, an internal write pulse is generated that loads the data into the memory cell.

and Spartan-XL families, speeding up arithmetic and counting functions.

The carry chain in 5V Spartan devices can run either up or down. At the top and bottom of the columns where there are no CLBs above and below, the carry is propagated to the right. The default is always to propagate up the column, as shown in the figures. The carry chain in Spartan-XL devices can only run up the column, providing even higher speed.

Figure 16, page 18 shows a Spartan/XL FPGA CLB with dedicated fast carry logic. The carry logic shares operand and control inputs with the function generators. The carry outputs connect to the function generators, where they are combined with the operands to form the sums.

Figure 17, page 19 shows the details of the Spartan/XL FPGA carry logic. This diagram shows the contents of the box labeled "CARRY LOGIC" in Figure 16.

The fast carry logic can be accessed by placing special library symbols, or by using Xilinx Relationally Placed Macros (RPMs) that already include these symbols.

On-Chip Oscillator

Spartan/XL devices include an internal oscillator. This oscillator is used to clock the power-on time-out, for configuration memory clearing, and as the source of CCLK in Master configuration mode. The oscillator runs at a nominal 8 MHz frequency that varies with process, V_{CC}, and temperature. The output frequency falls between 4 MHz and 10 MHz.

The oscillator output is optionally available after configuration. Any two of four resynchronized taps of a built-in divider are also available. These taps are at the fourth, ninth, fourteenth and nineteenth bits of the divider. Therefore, if the primary oscillator output is running at the nominal 8 MHz, the user has access to an 8-MHz clock, plus any two of 500 kHz, 16 kHz, 490 Hz and 15 Hz. These frequencies can vary by as much as -50% or +25%.

These signals can be accessed by placing the OSC4 library element in a schematic or in HDL code. The oscillator is automatically disabled after configuration if the OSC4 symbol is not used in the design.

Global Signals: GSR and GTS

Global Set/Reset

A separate Global Set/Reset line, as shown in Figure 3, page 5 for the CLB and Figure 5, page 6 for the IOB, sets or clears each flip-flop during power-up, reconfiguration, or when a dedicated Reset net is driven active. This global net (GSR) does not compete with other routing resources; it uses a dedicated distribution network.

Each flip-flop is configured as either globally set or reset in the same way that the local set/reset (SR) is specified. Therefore, if a flip-flop is set by SR, it is also set by GSR. Similarly, if in reset mode, it is reset by both SR and GSR.

GSR can be driven from any user-programmable pin as a global reset input. To use this global net, place an input pad and input buffer in the schematic or HDL code, driving the GSR pin of the STARTUP symbol. (See Figure 19.) A specific pin location can be assigned to this input using a LOC attribute or property, just as with any other user-programmable pad. An inverter can optionally be inserted after the input buffer to invert the sense of the GSR signal. Alternatively, GSR can be driven from any internal node.

Global 3-State

A separate Global 3-state line (GTS) as shown in Figure 6, page 7 forces all FPGA outputs to the high-impedance state, unless boundary scan is enabled and is executing an EXTEST instruction. GTS does not compete with other routing resources; it uses a dedicated distribution network.

GTS can be driven from any user-programmable pin as a global 3-state input. To use this global net, place an input pad and input buffer in the schematic or HDL code, driving the GTS pin of the STARTUP symbol. This is similar to what is shown in Figure 19 for GSR except the IBUF would be connected to GTS. A specific pin location can be assigned to this input using a LOC attribute or property, just as with any other user-programmable pad. An inverter can optionally be inserted after the input buffer to invert the sense of the Global 3-state signal. Alternatively, GTS can be driven from any internal node.

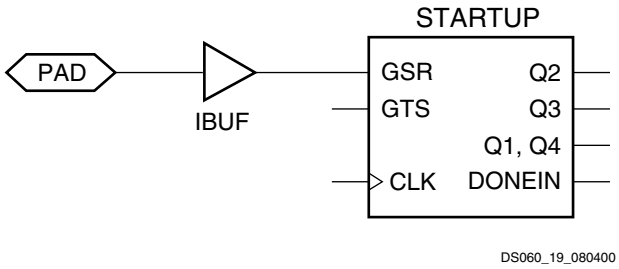


Figure 19: **Symbols for Global Set/Reset**

Boundary Scan

The "bed of nails" has been the traditional method of testing electronic assemblies. This approach has become less appropriate, due to closer pin spacing and more sophisticated assembly methods like surface-mount technology and multi-layer boards. The IEEE Boundary Scan Standard 1149.1 was developed to facilitate board-level testing of electronic assemblies. Design and test engineers can embed a standard test logic structure in their device to achieve high fault coverage for I/O and internal logic. This structure is easily implemented with a four-pin interface on any boundary scan compatible device. IEEE 1149.1-compatible devices may be serial daisy-chained together, connected in parallel, or a combination of the two.

The Spartan and Spartan-XL families implement IEEE 1149.1-compatible BYPASS, PRELOAD/SAMPLE and EXTEST boundary scan instructions. When the boundary scan configuration option is selected, three normal user I/O pins become dedicated inputs for these functions. Another user output pin becomes the dedicated boundary scan output. The details of how to enable this circuitry are covered later in this section.

By exercising these input signals, the user can serially load commands and data into these devices to control the driving of their outputs and to examine their inputs. This method is an improvement over bed-of-nails testing. It avoids the need to over-drive device outputs, and it reduces the user interface to four pins. An optional fifth pin, a reset for the control logic, is described in the standard but is not implemented in the Spartan/XL devices.

The dedicated on-chip logic implementing the IEEE 1149.1 functions includes a 16-state machine, an instruction register and a number of data registers. The functional details can be found in the IEEE 1149.1 specification and are also discussed in the Xilinx application note: "*Boundary Scan in FPGA Devices*."

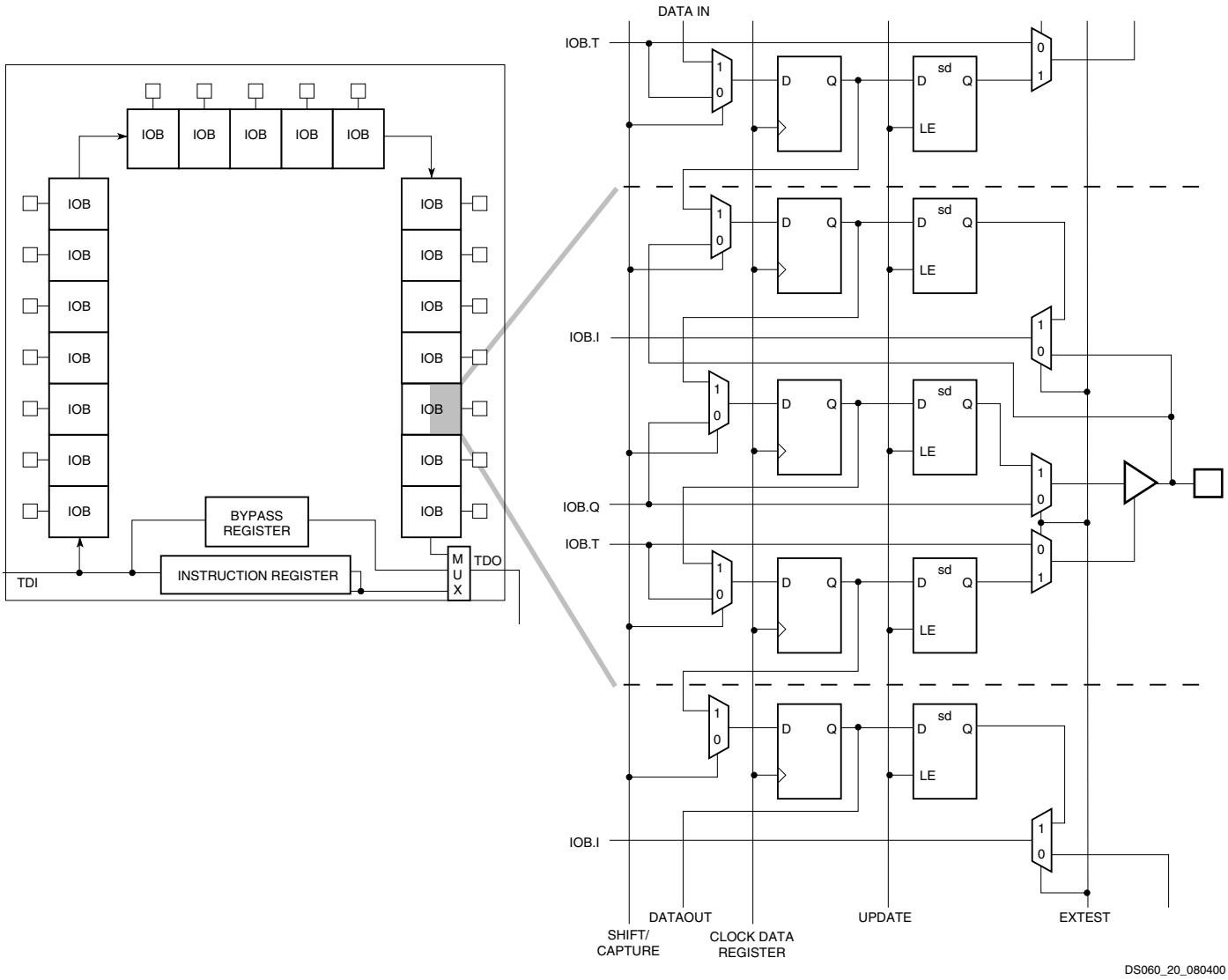
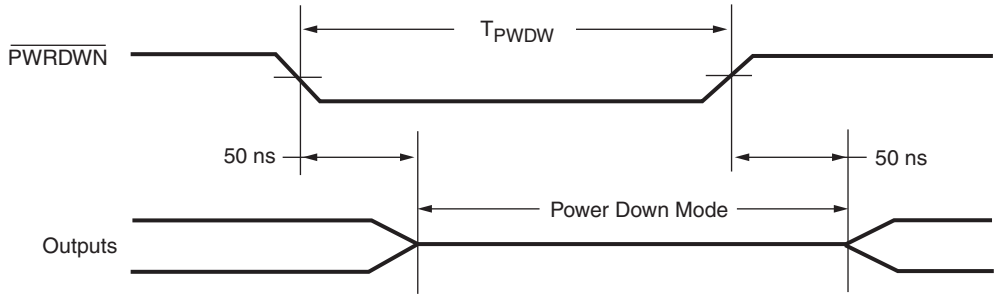


Figure 20: **Spartan/XL Boundary Scan Logic**



Description	Symbol	Min
Power Down Time	T_{PWD}	50 ns
Power Down Pulse Width	T_{PWDW}	50 ns

DS060_23_041901

Figure 23: **$\overline{\text{PWRDWN}}$ Pulse Timing**

Power-down retains the configuration, but loses all data stored in the device flip-flops. All inputs are interpreted as Low, but the internal combinatorial logic is fully functional. Make sure that the combination of all inputs Low and all flip-flops set or reset in your design will not generate internal oscillations, or create permanent bus contention by activating internal bus drivers with conflicting data onto the same long line.

During configuration, the $\overline{\text{PWRDWN}}$ pin must be High. If the Power Down state is entered before or during configuration, the device will restart configuration once the $\overline{\text{PWRDWN}}$ signal is removed. Note that the configuration pins are affected by Power Down and may not reflect their normal function. If there is an external pull-up resistor on the DONE pin, it will be High during Power Down even if the device is not yet configured. Similarly, if $\overline{\text{PWRDWN}}$ is asserted before configuration is completed, the $\overline{\text{INIT}}$ pin will not indicate status information.

Note that the $\overline{\text{PWRDWN}}$ pin is not part of the Boundary Scan chain. Therefore, the Spartan-XL family has a separate set of BSDL files than the 5V Spartan family. Boundary scan logic is not usable during Power Down.

Configuration and Test

Configuration is the process of loading design-specific programming data into one or more FPGAs to define the functional operation of the internal blocks and their interconnections. This is somewhat like loading the command registers of a programmable peripheral chip. Spartan/XL devices use several hundred bits of configuration data per CLB and its associated interconnects. Each configuration bit defines the state of a static memory cell that controls either a function look-up table bit, a multiplexer input, or an interconnect pass transistor. The Xilinx development system translates the design into a netlist file. It automatically partitions, places and routes the logic and generates the configuration data in PROM format.

Configuration Mode Control

5V Spartan devices have two configuration modes.

- MODE = 1 sets Slave Serial mode
- MODE = 0 sets Master Serial mode

3V Spartan-XL devices have three configuration modes.

- M1/M0 = 11 sets Slave Serial mode
- M1/M0 = 10 sets Master Serial mode
- M1/M0 = 0X sets Express mode

In addition to these modes, the device can be configured through the Boundary Scan logic (See "Configuration Through the Boundary Scan Pins" on page 37.).

The Mode pins are sampled prior to starting configuration to determine the configuration mode. After configuration, these pin are unused. The Mode pins have a weak pull-up resistor turned on during configuration. With the Mode pins High, Slave Serial mode is selected, which is the most popular configuration mode. Therefore, for the most common configuration mode, the Mode pins can be left unconnected. If the Master Serial mode is desired, the MODE/M0 pin should be connected directly to GND, or through a pull-down resistor of 1 KΩ or less.

During configuration, some of the I/O pins are used temporarily for the configuration process. All pins used during con-

figuration are shown in Table 14 and Table 15.

Table 14: **Pin Functions During Configuration (Spartan Family Only)**

Configuration Mode (MODE Pin)		User Operation
Slave Serial (High)	**Master Serial (Low)**	
MODE (I)	MODE (I)	MODE
HDC (High)	HDC (High)	I/O
$\overline{\text{LDC}}$ (Low)	$\overline{\text{LDC}}$ (Low)	I/O
$\overline{\text{INIT}}$	$\overline{\text{INIT}}$	I/O
DONE	DONE	DONE
$\overline{\text{PROGRAM}}$ (I)	$\overline{\text{PROGRAM}}$ (I)	$\overline{\text{PROGRAM}}$
CCLK (I)	CCLK (O)	CCLK (I)
DIN (I)	DIN (I)	I/O
DOUT	DOUT	SGCK4-I/O
TDI	TDI	TDI-I/O
TCK	TCK	TCK-I/O
TMS	TMS	TMS-I/O
TDO	TDO	TDO-(O)
		ALL OTHERS

Notes:
1. A shaded table cell represents the internal pull-up used before and during configuration.
2. (I) represents an input; (O) represents an output.
3. $\overline{\text{INIT}}$ is an open-drain output during configuration.

Table 15: **Pin Functions During Configuration (Spartan-XL Family Only)**

CONFIGURATION MODE <M1:M0>			User Operation
Slave Serial [1:1]	**Master Serial [1:0]**	**Express [0:X]**	
M1 (High) (I)	M1 (High) (I)	M1(Low) (I)	M1
M0 (High) (I)	M0 (Low) (I)	M0 (I)	M0
HDC (High)	HDC (High)	HDC (High)	I/O
$\overline{\text{LDC}}$ (Low)	$\overline{\text{LDC}}$ (Low)	$\overline{\text{LDC}}$ (Low)	I/O
$\overline{\text{INIT}}$	$\overline{\text{INIT}}$	$\overline{\text{INIT}}$	I/O
DONE	DONE	DONE	DONE
$\overline{\text{PROGRAM}}$ (I)	$\overline{\text{PROGRAM}}$ (I)	$\overline{\text{PROGRAM}}$ (I)	$\overline{\text{PROGRAM}}$
CCLK (I)	CCLK (O)	CCLK (I)	CCLK (I)
		DATA 7 (I)	I/O
		DATA 6 (I)	I/O
		DATA 5 (I)	I/O
		DATA 4 (I)	I/O
		DATA 3 (I)	I/O
		DATA 2 (I)	I/O
		DATA 1 (I)	I/O
DIN (I)	DIN (I)	DATA 0 (I)	I/O
DOUT	DOUT	DOUT	GCK6-I/O
TDI	TDI	TDI	TDI-I/O
TCK	TCK	TCK	TCK-I/O
TMS	TMS	TMS	TMS-I/O
TDO	TDO	TDO	TDO-(O)
		CS1	I/O
			ALL OTHERS

Notes:
1. A shaded table cell represents the internal pull-up used before and during configuration.
2. (I) represents an input; (O) represents an output.
3. $\overline{\text{INIT}}$ is an open-drain output during configuration.

to the DONE pin. User I/Os for each device become active after the DONE pin for that device goes High. (The exact timing is determined by development system options.) Since the DONE pin is open-drain and does not drive a High value, tying the DONE pins of all devices together prevents all devices in the chain from going High until the last device in the chain has completed its configuration cycle. If the DONE pin of a device is left unconnected, the device becomes active as soon as that device has been configured. Only devices supporting Express mode can be used to form an Express mode daisy chain.

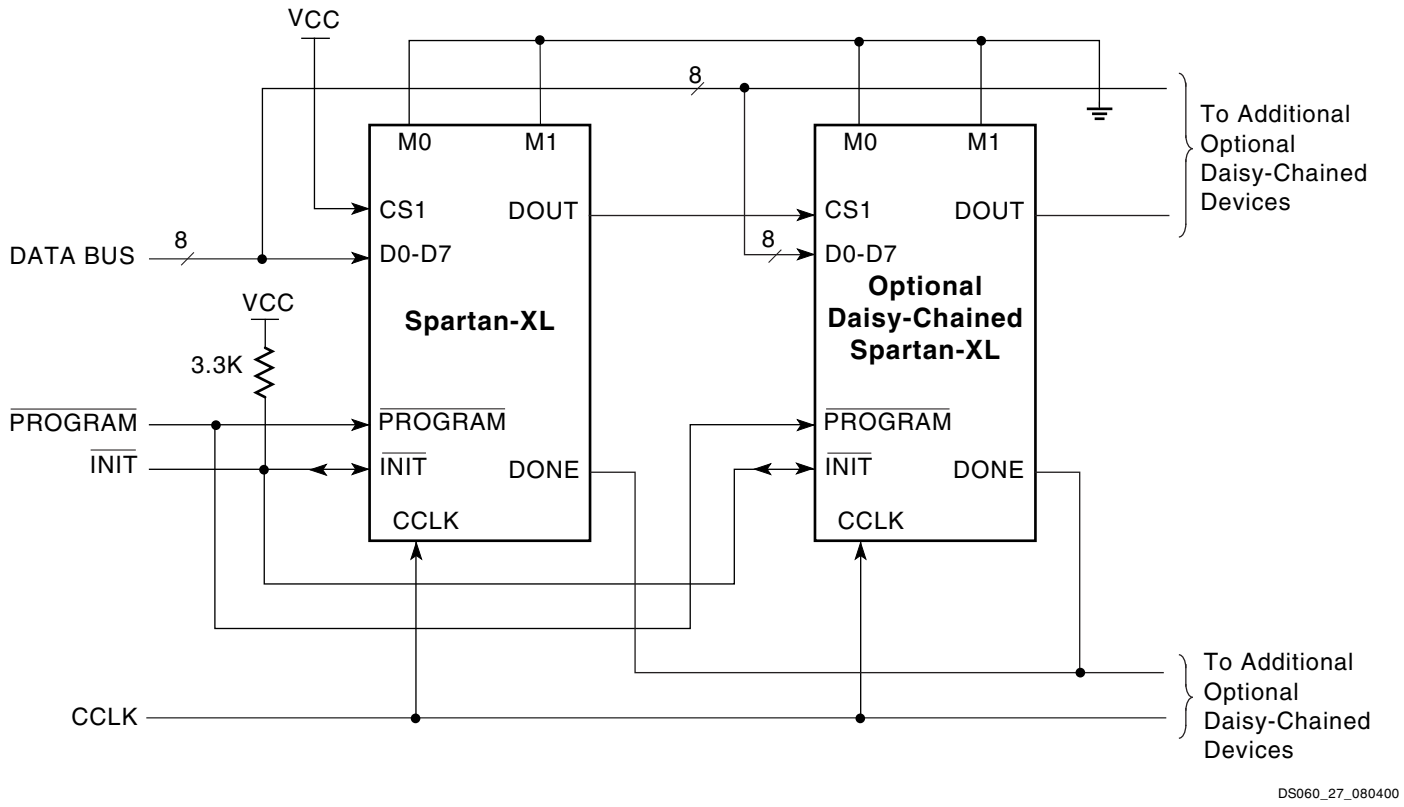
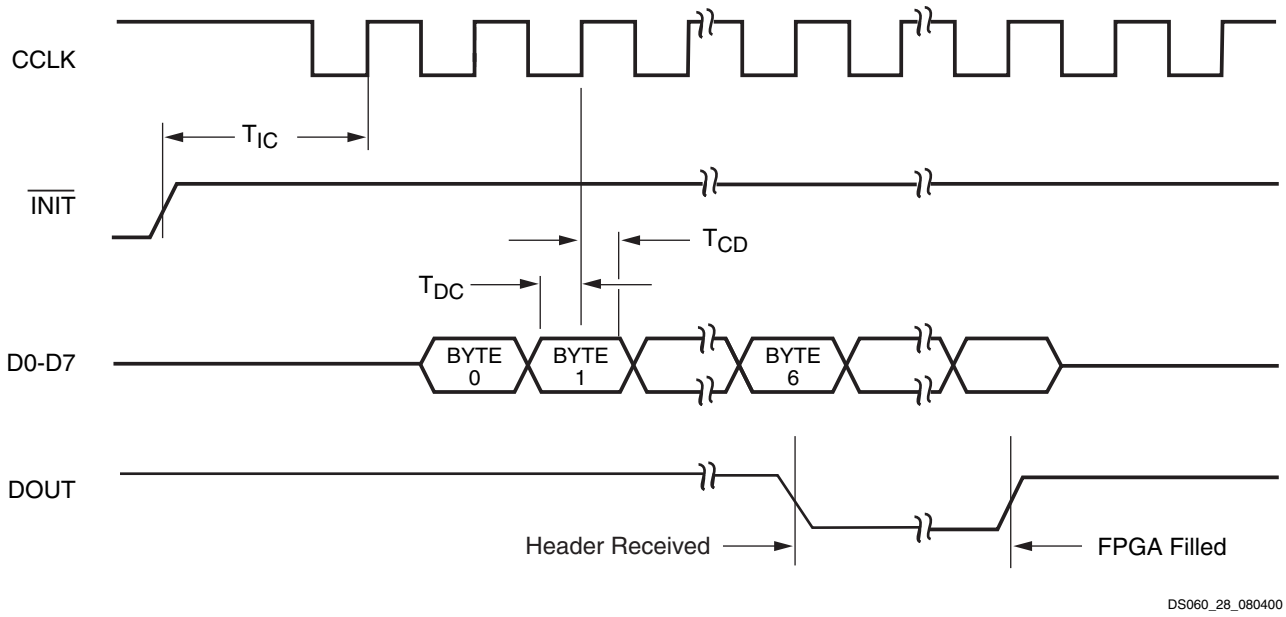


Figure 27: **Express Mode Circuit Diagram**



Symbol		Description	Min	Max	Units
T_{IC}	CCLK	$\overline{INIT}$ (High) setup time	5	-	µs
T_{DC}		D0-D7 setup time	20	-	ns
T_{CD}		D0-D7 hold time	0	-	ns
T_{CCH}		CCLK High time	45	-	ns
T_{CCL}		CCLK Low time	45	-	ns
F_{CC}		CCLK Frequency	-	10	MHz

Notes:
1. If not driven by the preceding DOUT, CS1 *must* remain High until the device is fully configured.

Figure 28: **Express Mode Programming Switching Characteristics**

Setting CCLK Frequency

In Master mode, CCLK can be generated in either of two frequencies. In the default slow mode, the frequency ranges from 0.5 MHz to 1.25 MHz for Spartan/XL devices. In fast CCLK mode, the frequency ranges from 4 MHz to 10 MHz for Spartan/XL devices. The frequency is changed to fast by an option when running the bitstream generation software.

Data Stream Format

The data stream ("bitstream") format is identical for both serial configuration modes, but different for the Spartan-XL family Express mode. In Express mode, the device becomes active when DONE goes High, therefore no length count is required. Additionally, CRC error checking is not supported in Express mode. The data stream format is shown in Table 16. Bit-serial data is read from left to right. Express mode data is shown with D0 at the left and D7 at the right.

The configuration data stream begins with a string of eight ones, a preamble code, followed by a 24-bit length count and a separator field of ones (or 24 fill bits, in Spartan-XL family Express mode). This header is followed by the actual configuration data in frames. The length and number of frames depends on the device type (see Table 17). Each frame begins with a start field and ends with an error check. In serial modes, a postamble code is required to signal the end of data for a single device. In all cases, additional start-up bytes of data are required to provide four clocks for the startup sequence at the end of configuration. Long daisy chains require additional startup bytes to shift the last data through the chain. All start-up bytes are "don't cares".

Table 16: **Spartan/XL Data Stream Formats**

Data Type	Serial Modes (D0...)	Express Mode (D0-D7) (Spartan-XL only)
Fill Byte	11111111b	FFFFh
Preamble Code	0010b	11110010b
Length Count	COUNT[23:0]	COUNT[23:0](1)
Fill Bits	1111b	-
Field Check Code	-	11010010b
Start Field	0b	11111110b(2)
Data Frame	DATA[n–1:0]	DATA[n–1:0]
CRC or Constant Field Check	xxxx (CRC) or 0110b	11010010b
Extend Write Cycle	-	FFD2FFFFFFh
Postamble	01111111b	-
Start-Up Bytes(3)	FFh	FFFFFFFFFFFFFFh

Legend:

Unshaded	Once per bitstream
Light	Once per data frame
Dark	Once per device

Notes:
1. Not used by configuration logic.
2. 11111111b for XCS40XL only.
3. Development system may add more start-up bytes.

A selection of CRC or non-CRC error checking is allowed by the bitstream generation software. The Spartan-XL family Express mode only supports non-CRC error checking. The non-CRC error checking tests for a designated end-of-frame field for each frame. For CRC error checking, the software calculates a running CRC and inserts a unique four-bit partial check at the end of each frame. The 11-bit CRC check of the last frame of an FPGA includes the last seven data bits.

Detection of an error results in the suspension of data loading before DONE goes High, and the pulling down of the $\overline{\text{INIT}}$ pin. In Master serial mode, CCLK continues to operate externally. The user must detect $\overline{\text{INIT}}$ and initialize a new configuration by pulsing the $\overline{\text{PROGRAM}}$ pin Low or cycling V_{CC}.

Cyclic Redundancy Check (CRC) for Configuration and Readback

The Cyclic Redundancy Check is a method of error detection in data transmission applications. Generally, the transmitting system performs a calculation on the serial bitstream. The result of this calculation is tagged onto the data stream as additional check bits. The receiving system performs an identical calculation on the bitstream and compares the result with the received checksum.

Each data frame of the configuration bitstream has four error bits at the end, as shown in Table 16. If a frame data error is detected during the loading of the FPGA, the configuration process with a potentially corrupted bitstream is terminated. The FPGA pulls the $\overline{\text{INIT}}$ pin Low and goes into a Wait state.

Table 17: **Spartan/XL Program Data**

Device	XCS05		XCS10		XCS20		XCS30		XCS40	
Max System Gates	5,000		10,000		20,000		30,000		40,000	
CLBs (Row x Col.)	100 (10 x 10)		196 (14 x 14)		400 (20 x 20)		576 (24 x 24)		784 (28 x 28)	
IOBs	80		112		160		192		205(4)	
Part Number	XCS05	XCS05XL	XCS10	XCS10XL	XCS20	XCS20XL	XCS30	XCS30XL	XCS40	XCS40XL
Supply Voltage	5V	3.3V	5V	3.3V	5V	3.3V	5V	3.3V	5V	3.3V
Bits per Frame	126	127	166	167	226	227	266	267	306	307
Frames	428	429	572	573	788	789	932	933	1,076	1,077
Program Data	53,936	54,491	94,960	95,699	178,096	179,111	247,920	249,119	329,264	330,647
PROM Size (bits)	53,984	54,544	95,008	95,752	178,144	179,160	247,968	249,168	329,312	330,696
Express Mode PROM Size (bits)	-	79,072	-	128,488	-	221,056	-	298,696	-	387,856

Notes:

1. Bits per Frame = (10 x number of rows) + 7 for the top + 13 for the bottom + 1 + 1 start bit + 4 error check bits (+1 for Spartan-XL device)
   Number of Frames = (36 x number of columns) + 26 for the left edge + 41 for the right edge + 1 (+ 1 for Spartan-XL device)
   Program Data = (Bits per Frame x Number of Frames) + 8 postamble bits
   PROM Size = Program Data + 40 (header) + 8, rounded up to the nearest byte
2. The user can add more "1" bits as leading dummy bits in the header, or, if CRC = off, as trailing dummy bits at the end of any frame, following the four error check bits. However, the Length Count value **must** be adjusted for all such extra "one" bits, even for extra leading ones at the beginning of the header.
3. Express mode adds 57 (XCS05XL, XCS10XL), or 53 (XCS20XL, XCS30XL, XCS40XL) bits per frame, + additional start-up bits.
4. XCS40XL provided 224 max I/O in CS280 package discontinued by PDN2004-01.

During Readback, 11 bits of the 16-bit checksum are added to the end of the Readback data stream. The checksum is computed using the CRC-16 CCITT polynomial, as shown in Figure 29. The checksum consists of the 11 most significant bits of the 16-bit code. A change in the checksum indicates a change in the Readback bitstream. A comparison to a previous checksum is meaningful only if the readback data is independent of the current device state. CLB outputs should not be included (Readback Capture option not used), and if RAM is present, the RAM content must be unchanged.

Statistically, one error out of 2048 might go undetected.

Readback Switching Characteristics Guidelines

The following guidelines reflect worst-case values over the recommended operating conditions.

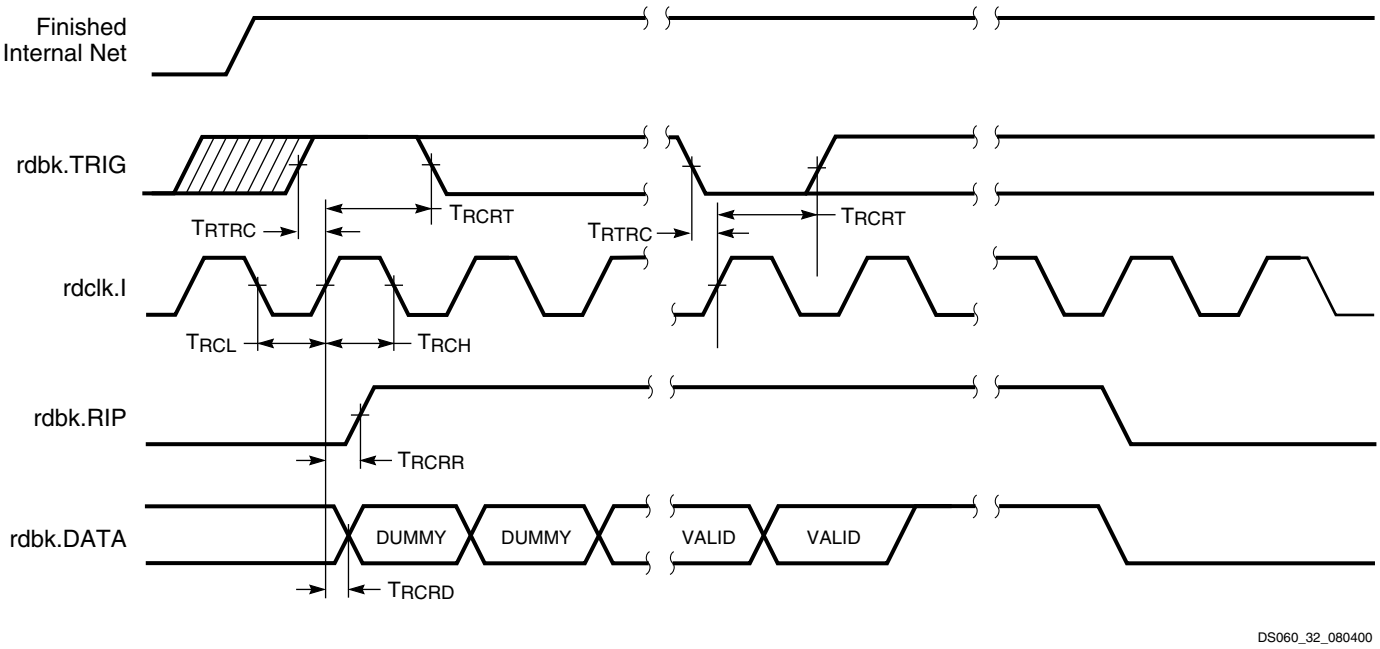


Figure 33: **Spartan and Spartan-XL Readback Timing Diagram**

Spartan and Spartan-XL Readback Switching Characteristics

Symbol		Description	Min	Max	Units
T_{RTRC}	rdbk.TRIG	rdbk.TRIG setup to initiate and abort Readback	200	-	ns
T_{RCRT}		rdbk.TRIG hold to initiate and abort Readback	50	-	ns
T_{RCRD}	rdclk.I	rdbk.DATA delay	-	250	ns
T_{RCRR}		rdbk.RIP delay	-	250	ns
T_{RCH}		High time	250	500	ns
T_{RCL}		Low time	250	500	ns

Notes:
1. Timing parameters apply to all speed grades.
2. If rdbk.TRIG is High prior to Finished, Finished will trigger the first Readback.

Spartan Family IOB Output Switching Characteristic Guidelines

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation netlist. These path delays, provided as a guideline, have been extracted from the static timing analyzer report. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature). Values are expressed in nanoseconds unless otherwise noted.

Symbol	Description	Device	Speed Grade				Units
			-4		-3		
			Min	Max	Min	Max	
Clocks							
T_{CH}	Clock High	All devices	3.0	-	4.0	-	ns
T_{CL}	Clock Low	All devices	3.0	-	4.0	-	ns
Propagation Delays - TTL Outputs(1,2)							
T_{OKPOF}	Clock (OK) to Pad, fast	All devices	-	3.3	-	4.5	ns
T_{OKPOS}	Clock (OK to Pad, slew-rate limited	All devices	-	6.9	-	7.0	ns
T_{OPF}	Output (O) to Pad, fast	All devices	-	3.6	-	4.8	ns
T_{OPS}	Output (O) to Pad, slew-rate limited	All devices	-	7.2	-	7.3	ns
T_{TSHZ}	3-state to Pad High-Z (slew-rate independent)	All devices	-	3.0	-	3.8	ns
T_{TSONF}	3-state to Pad active and valid, fast	All devices	-	6.0	-	7.3	ns
T_{TSONS}	3-state to Pad active and valid, slew-rate limited	All devices	-	9.6	-	9.8	ns
Setup and Hold Times							
T_{OOK}	Output (O) to clock (OK) setup time	All devices	2.5	-	3.8	-	ns
T_{OKO}	Output (O) to clock (OK) hold time	All devices	0.0	-	0.0	-	ns
T_{ECOK}	Clock Enable (EC) to clock (OK) setup time	All devices	2.0	-	2.7	-	ns
T_{OKEC}	Clock Enable (EC) to clock (OK) hold time	All devices	0.0	-	0.5	-	ns
Global Set/Reset							
T_{MRW}	Minimum GSR pulse width	All devices	11.5		13.5		ns
T_{RPO}	Delay from GSR input to any Pad	XCS05	-	12.0	-	15.0	ns
		XCS10	-	12.5	-	15.7	ns
		XCS20	-	13.0	-	16.2	ns
		XCS30	-	13.5	-	16.9	ns
		XCS40	-	14.0	-	17.5	ns

Notes:

1. Delay adder for CMOS Outputs option (with fast slew rate option): for -3 speed grade, add 1.0 ns; for -4 speed grade, add 0.8 ns.
2. Delay adder for CMOS Outputs option (with slow slew rate option): for -3 speed grade, add 2.0 ns; for -4 speed grade, add 1.5 ns.
3. Output timing is measured at ~50% V_{CC} threshold, with 50 pF external capacitive loads including test fixture. Slew-rate limited output rise/fall times are approximately two times longer than fast output rise/fall times.
4. Voltage levels of unused pads, bonded or unbonded, must be valid logic levels. Each can be configured with the internal pull-up (default) or pull-down resistor, or configured as a driven output, or can be driven from an external source.

Spartan-XL Family DC Characteristics Over Operating Conditions

Symbol	Description		Min	Typ.	Max	Units
V_{OH}	High-level output voltage @ I_{OH} = –4.0 mA, V_{CC} min (LVTTL)		2.4	-	-	V
	High-level output voltage @ I_{OH} = –500 µA, (LVCMOS)		90% V_{CC}	-	-	V
V_{OL}	Low-level output voltage @ I_{OL} = 12.0 mA, V_{CC} min (LVTTL)(1)		-	-	0.4	V
	Low-level output voltage @ I_{OL} = 24.0 mA, V_{CC} min (LVTTL)(2)		-	-	0.4	V
	Low-level output voltage @ I_{OL} = 1500 µA, (LVCMOS)		-	-	10% V_{CC}	V
V_{DR}	Data retention supply voltage (below which configuration data may be lost)		2.5	-	-	V
I_{CCO}	Quiescent FPGA supply current(3,4)	Commercial	-	0.1	2.5	mA
		Industrial	-	0.1	5	mA
I_{CCPD}	Power Down FPGA supply current(3,5)	Commercial	-	0.1	2.5	mA
		Industrial	-	0.1	5	mA
I_L	Input or output leakage current		–10	-	10	µA
C_{IN}	Input capacitance (sample tested)		-	-	10	pF
I_{RPU}	Pad pull-up (when selected) @ V_{IN} = 0V (sample tested)		0.02	-	0.25	mA
I_{RPD}	Pad pull-down (when selected) @ V_{IN} = 3.3V (sample tested)		0.02	-	-	mA

Notes:
1. With up to 64 pins simultaneously sinking 12 mA (default mode).
2. With up to 64 pins simultaneously sinking 24 mA (with 24 mA option selected).
3. With 5V tolerance not selected, no internal oscillators, and the FPGA configured with the Tie option.
4. With no output current loads, no active input resistors, and all package pins at V_{CC} or GND.
5. With $\overline{PWRDWN}$ active.

Supply Current Requirements During Power-On

Spartan-XL FPGAs require that a minimum supply current I_{CCPO} be provided to the V_{CC} lines for a successful power on. If more current is available, the FPGA can consume more than I_{CCPO} min., though this cannot adversely affect reliability.

A maximum limit for I_{CCPO} is not specified. Be careful when using foldback/crowbar supplies and fuses. It is possible to control the magnitude of I_{CCPO} by limiting the supply current available to the FPGA. A current limit below the trip level will avoid inadvertently activating over-current protection circuits.

Symbol	Description	Min	Max	Units
I_{CCPO}	Total V_{CC} supply current required during power-on	100	-	mA
T_{CCPO}	V_{CC} ramp time(2,3)	-	50	ms

Notes:
1. The I_{CCPO} requirement applies for a brief time (commonly only a few milliseconds) when V_{CC} ramps from 0 to 3.3V.
2. The ramp time is measured from GND to V_{CC} max on a fully loaded board.
3. V_{CC} must not dip in the negative direction during power on.

Spartan-XL Family CLB Switching Characteristic Guidelines

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation netlist. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature). Values apply to all Spartan-XL devices and expressed in nanoseconds unless otherwise noted.

Symbol	Description	Speed Grade				Units
		-5		-4		
		Min	Max	Min	Max	
Clocks						
T_{CH}	Clock High time	2.0	-	2.3	-	ns
T_{CL}	Clock Low time	2.0	-	2.3	-	ns
Combinatorial Delays						
T_{ILO}	F/G inputs to X/Y outputs	-	1.0	-	1.1	ns
T_{IHO}	F/G inputs via H to X/Y outputs	-	1.7	-	2.0	ns
T_{ITO}	F/G inputs via transparent latch to Q outputs	-	1.5	-	1.8	ns
T_{HH1O}	C inputs via H1 via H to X/Y outputs	-	1.5	-	1.8	ns
Sequential Delays						
T_{CKO}	Clock K to Flip-Flop or latch outputs Q	-	1.2	-	1.4	ns
Setup Time before Clock K						
T_{ICK}	F/G inputs	0.6	-	0.7	-	ns
T_{IHCK}	F/G inputs via H	1.3	-	1.6	-	ns
Hold Time after Clock K						
	All Hold times, all devices	0.0	-	0.0	-	ns
Set/Reset Direct						
T_{RPW}	Width (High)	2.5	-	2.8	-	ns
T_{RIO}	Delay from C inputs via S/R, going High to Q	-	2.3	-	2.7	ns
Global Set/Reset						
T_{MRW}	Minimum GSR Pulse Width	10.5	-	11.5	-	ns
T_{MRQ}	Delay from GSR input to any Q	See page 60 for T_{RRI} values per device.				
F_{TOG}	Toggle Frequency (MHz) (for export control purposes)	-	250	-	217	MHz

XCS30 and XCS30XL Device Pinouts *(Continued)*

XCS30/XL Pad Name	VQ100[5]	TQ144	PQ208	PQ240	BG256[5]	CS280[2,5]	Bndry Scan
I/O	-	-	P124	P144	M20	L19	493 [3]
I/O	-	-	P125	P145	L19	L18	496 [3]
I/O	P59	P86	P126	P146	L18	L17	499 [3]
I/O	P60	P87	P127	P147	L20	L16	502 [3]
I/O (D4[2])	P61	P88	P128	P148	K20	K19	505 [3]
I/O	P62	P89	P129	P149	K19	K18	508 [3]
VCC	P63	P90	P130	P150	VCC[4]	K17	-
GND	P64	P91	P131	P151	GND[4]	GND[4]	-
I/O (D3[2])	P65	P92	P132	P152	K18	K16	511 [3]
I/O	P66	P93	P133	P153	K17	K15	514 [3]
I/O	P67	P94	P134	P154	J20	J19	517 [3]
I/O	-	P95	P135	P155	J19	J18	520 [3]
I/O	-	-	P136	P156	J18	J17	523 [3]
I/O	-	-	P137	P157	J17	J16	526 [3]
I/O (D2[2])	P68	P96	P138	P159	H19	H17	529 [3]
I/O	P69	P97	P139	P160	H18	H16	532 [3]
VCC	-	-	P140	P161	VCC[4]	G19	-
I/O	-	P98	P141	P162	G19	G18	535 [3]
I/O	-	P99	P142	P163	F20	G17	538 [3]
I/O	-	-	-	P164	G18	G16	541 [3]
I/O	-	-	-	P165	F19	F19	544 [3]
GND	-	P100	P143	P166	GND[4]	GND[4]	-
I/O	-	-	-	P167	F18	F18	547 [3]
I/O	-	-	P144	P168	E19	F17	550 [3]
I/O	-	-	P145	P169	D20	F16	553 [3]
I/O	-	-	P146	P170	E18	F15	556 [3]
I/O	-	-	P147	P171	D19	E19	559 [3]
I/O	-	-	P148	P172	C20	E17	562 [3]
I/O (D1[2])	P70	P101	P149	P173	E17	E16	565 [3]
I/O	P71	P102	P150	P174	D18	D19	568 [3]
I/O	-	P103	P151	P175	C19	C19	571 [3]
I/O	-	P104	P152	P176	B20	B19	574 [3]
I/O (D0[2], DIN)	P72	P105	P153	P177	C18	C18	577 [3]
I/O, SGCK4[1], GCK6[2] (DOUT)	P73	P106	P154	P178	B19	B18	580 [3]
CCLK	P74	P107	P155	P179	A20	A19	-
VCC	P75	P108	P156	P180	VCC[4]	C17	-
O, TDO	P76	P109	P157	P181	A19	B17	0
GND	P77	P110	P158	P182	GND[4]	GND[4]	-
I/O	P78	P111	P159	P183	B18	A18	2
I/O, PGCK4[1], GCK7[2]	P79	P112	P160	P184	B17	A17	5
I/O	-	P113	P161	P185	C17	D16	8
I/O	-	P114	P162	P186	D16	C16	11
I/O (CS1)[2]	P80	P115	P163	P187	A18	B16	14
I/O	P81	P116	P164	P188	A17	A16	17
I/O	-	-	P165	P189	C16	D15	20

Revision History

The following table shows the revision history for this document.

Date	Version	Description
11/20/98	1.3	Added Spartan-XL specs and Power Down.
01/06/99	1.4	All Spartan-XL -4 specs designated Preliminary with no changes.
03/02/00	1.5	Added CS package, updated Spartan-XL specs to Final.
09/19/01	1.6	Reformatted, updated power specs, clarified configuration information. Removed T_{SOL} soldering information from Absolute Maximum Ratings table. Changed Figure 26: Slave Serial Mode Characteristics: T_{CCH}, T_{CCL} from 45 to 40 ns. Changed Master Mode Configuration Switching Characteristics: T_{CCLK} min. from 80 to 100 ns. Added Total Dist. RAM Bits to Table 1; added **Start-Up**, page 36 characteristics.
06/27/02	1.7	Clarified Express Mode pseudo daisy chain. Added new Industrial options. Clarified XCS30XL CS280 V_{CC} pinout.
06/26/08	1.8	Noted that PC84, CS144, and CS280 packages, and VQ100 and BG256 packages for XCS30 only, are discontinued by **PDN2004-01**. Extended description of recommended maximum delay of reconfiguration in **Delaying Configuration After Power-Up**, page 35. Added reference to Pb-free package options and provided link to **Package Specifications**, page 81. Updated links.
03/01/13	2.0	The products listed in this data sheet are obsolete. See **XCN10016** and **XCN11010** for further information.